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Cooperative Connected and Automated Mobility (CCAM): Technologies and Applications

Guest Editor:

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Deadline for manuscript submissions:

closed (30 September 2019)

Message from the Guest Editor

The main aim of this Special Issue is to seek high-quality submissions that highlight recent breakthroughs in CCAM technologies and applications regarding safety, security aspects, new vehicular sensors, communication protocol, ultra-reliable and low-latency communications, distributed control algorithms. The topics of interest include, but are not limited to:

- Fault-tolerance techniques and devices for CCAM
- Safety assessment of CCAM
- Design methodologies for CCAM applications
- Security, privacy and trust issues
- Flexible network architectures for CCAM
- Smart sensors for CCAM
- 5G and CCAM (network slicing, ultra-reliable low-latency communications, etc.)
- Vehicular communications (DSRC, ITS-G5, C-V2X, LTE-V, etc.)
- Field trials and lessons learned

Welcome to contribute!











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Editor-in-Chief

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Message from the Editor-in-Chief

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